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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/655,224	CHEN ET AL.	
Examiner	Art Unit	_
Sarah F. Hushand	1746	

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SEARCHED			
Class	Subclass	Date	Examiner
134	103.2,148, 181,153	3/20/2007	SEH
134	94.1,198	3/20/2007	SEH
.15	77,88.2	3/20/2007	SEH
15	102	3/20/2007	SEH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
134	103.2 148	3/20/2007	SEH
134	181,153	3/20/2007	SEH
134 ·	94.1,198	3/20/2007	SEH
15/77,8	8.2,102	3/20/2007	SEH

SEARCH NOT (INCLUDING SEARCH S		)
	DATE	EXMR
Updated search. See attached search strategy	3/20/2007	SEH
Updated Inventor search.	3/20/2007	SEH